Temperature Sensors

What is the best sensor to measure temperature?

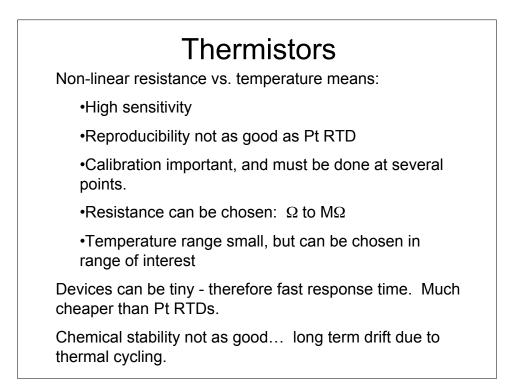
There is no such thing... depends on the temperature range, the accuracy needed, the environment, the cost, etc.

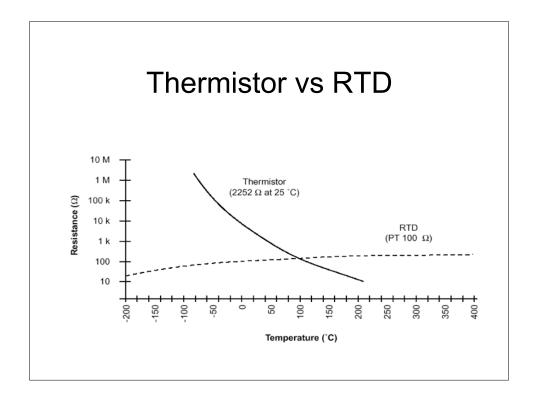
We have looked at RTDs, which have their electrical resistance vary with temperature. We then studied how to measure resistance.

NOTE: While we talked about measuring resistance in the context of thermometry, the tips we used are general, and apply to measuring resistance for other reasons too. We will revisit this later today and in future lectures.

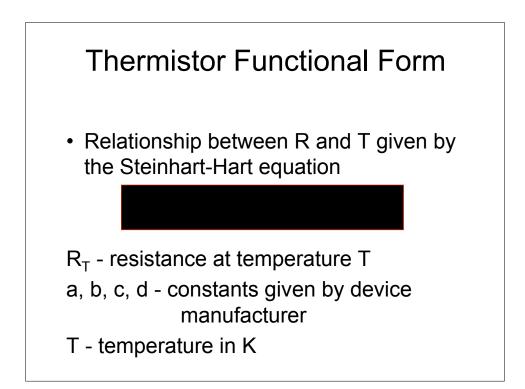
Thermistors

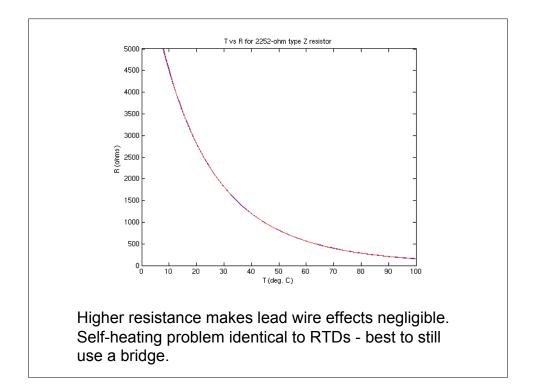
- Solid-state semiconductor device
 - Positive temperature coefficient (PTC) devices increases resistance with temperature increase
 - Negative temperature coefficient (NTC) devices decreases resistance with temperature increase
- Relationship between R and T is non-linear, but has a very steep slope
 - Increases the sensitivity of the device
 - Resistance change of 3%/°C
 - Limits range of operation

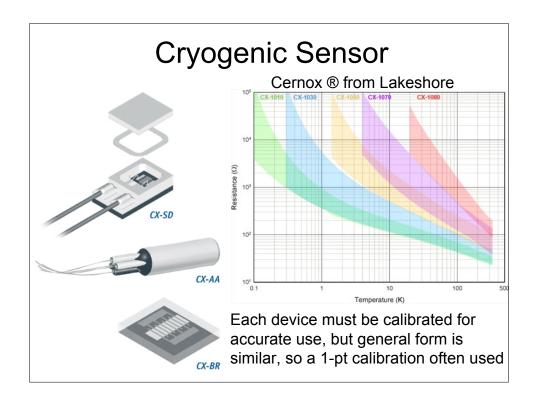


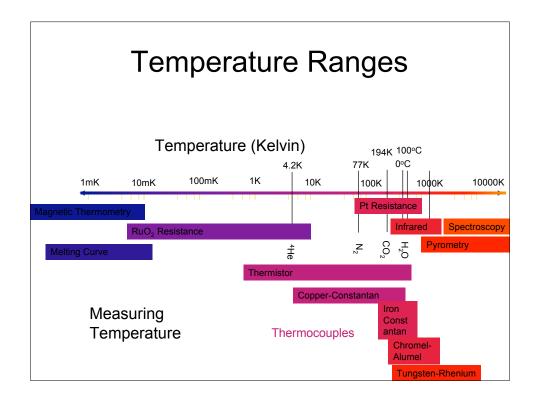


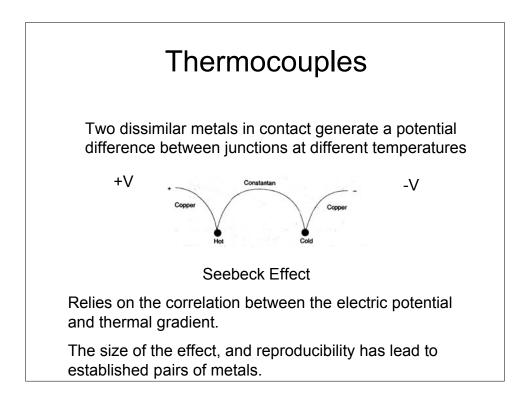


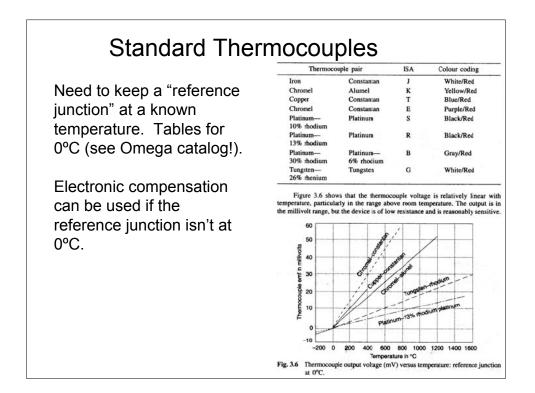


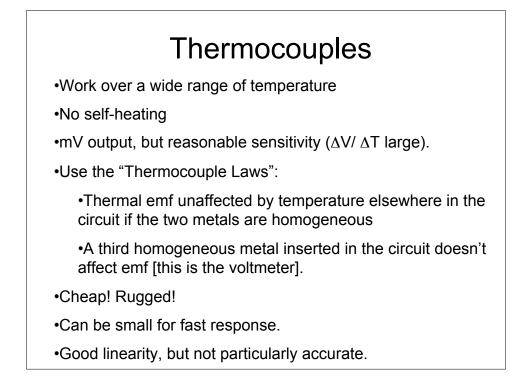


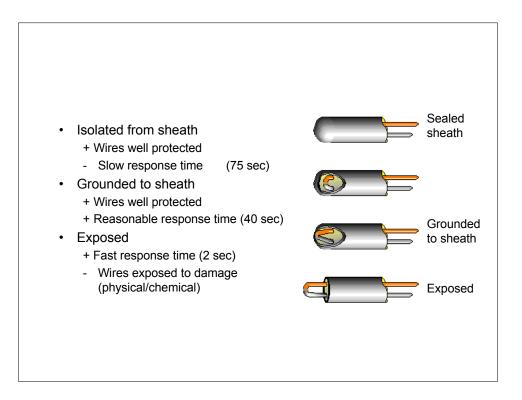






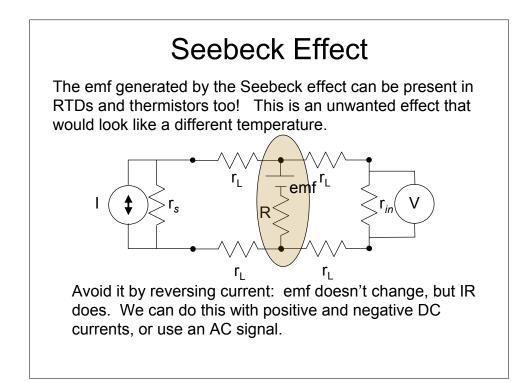


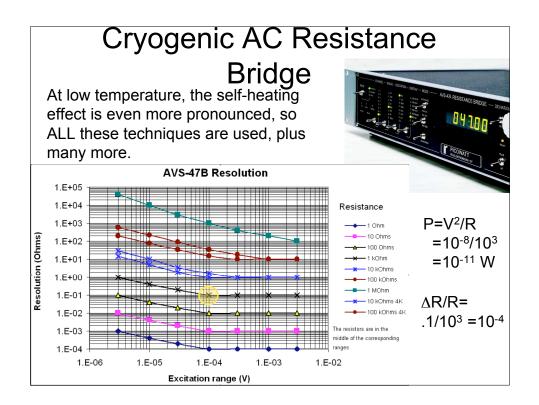




| Thermocouples | | | |
|---------------|---------------------------------|-----------------------|----------------------|
| Standard Type | Positive Leg Metal | Negative Leg Metal | Temperature Range |
| В | 70.4% Pt 29.6% Rh | 93.9% Pt 6.1% Rh | 870 - 1700 0°C |
| E | 90% Ni 10% Cr | 55% Cu 45% Ni | 0 - 900 0°C |
| J | 99.5% Fe | 55% Cu 45% Ni | 0 - 750 0°C |
| К | 90% Ni 10% Cr | 95% Ni 5% other | 0 - 1250 0°C |
| N | 84.4% Ni 14.2% Cr 1.4% Si | 95.5% Ni 4.4% Si | 0 - 1250 0°C |
| R | 87% Pt 13% Rh | 100% Pt | 0 - 1450 0°C |
| S | 90% Pt 10% Rh | 100% Pt | 0 - 1450 0°C |
| Т | 100% Cu | 55% Cu 45% Ni | -200 - 350 0°C |

*Modified from *Temperature Sensors,* The Watlow Educational Series Book Four





Junction Semiconductor Sensors

Silicon transistors configured in a circuit that has measurable and predictable I-V. Different configurations possible.

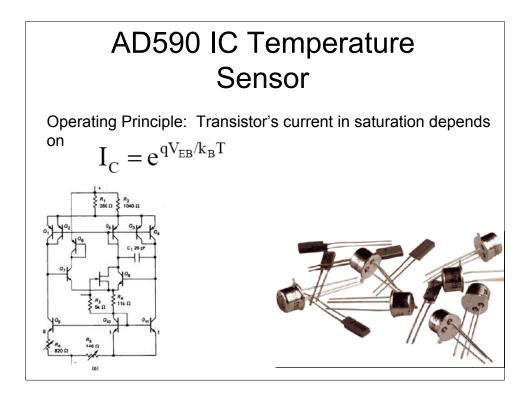
Benefits:

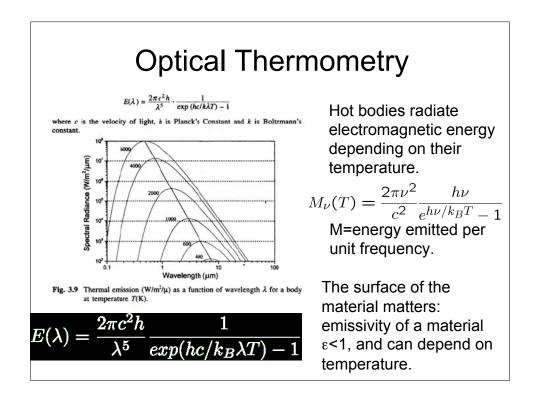
Cheap

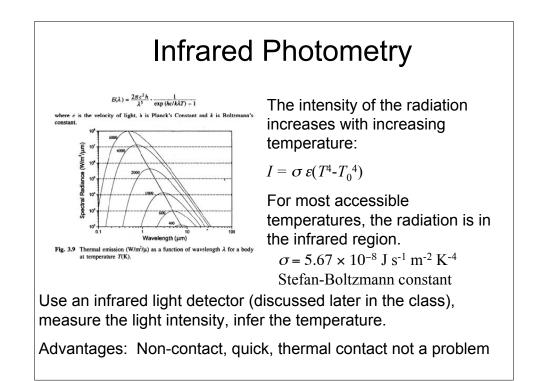
•Integrated with other silicon circuits (for memory, communication, amplification, processing, etc.)

Disadvantages

•Needs power, not rugged, not standardized, limited temperature range







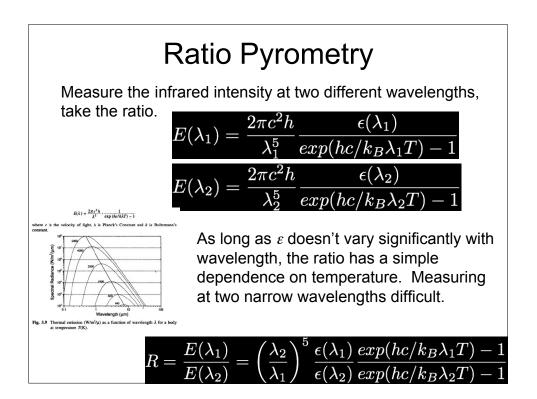
Infrared Photometry

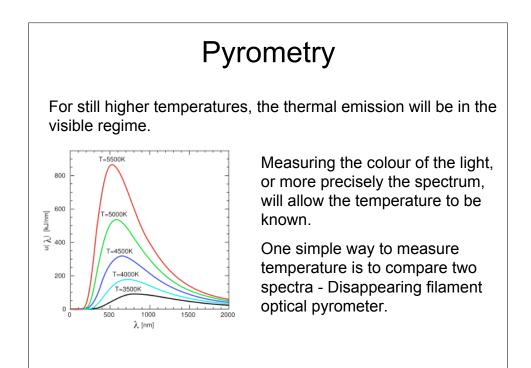
 $I = \sigma \, \varepsilon (T^4 \text{-} T_0^4)$

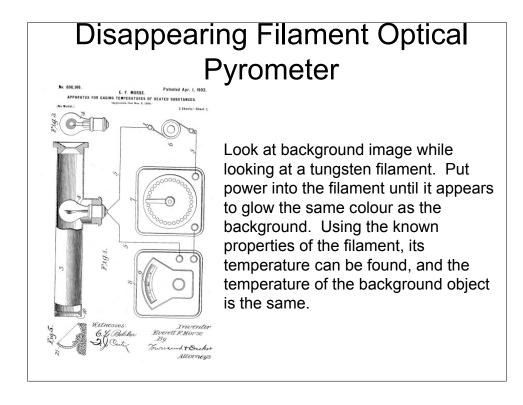
 ϵ is the emissivity - a number between 0 and 1 which defines how close to a "black body" (perfect emitter) the material is. No material is perfect, and surface changes result in changes to the emissivity.

The "grey body" approximation sets ε as a constant for all wavelengths.

Accurate measurements of ε are difficult, and are likely to change. Thus accuracy of infrared photometry is limited by the knowledge of the emissivity.







Measurement & Uncertainties

Anytime you make a measurement, you should quote an uncertainty on that measurement. This uncertainty tells the reader how confident you are in the number and takes into account two effects:

Statistical uncertainty: due to the random nature of some processes, we expect there to be variation in the measured values. For example: nuclear decay is a perfectly random event, so counting the number of decays in a given time will have some variation.

Statistical uncertainties happen whenever randomness is inherent:

- Nuclear decay
- -quantum processes
- -sampling of a larger ensemble

Measurement and Uncertainties

Systematic Uncertainties:

"Systematic Uncertainty: This is the degree to which a measured value differs from the 'true' value because of errors inherent in the measurement. This may be due to an incorrect scale, a wrong calibration or an erroneous assumption. In instrumentation, changes in the original calibration of an instrument over time, or if the instrument is used under abnormal conditions are major sources of systematic error. Systematic errors are generally not statistical in nature and may be corrected by measurement of a standard."

From textbook

Measurement and Uncertainties

These definitions are rather narrow, and exclude lots of other errors:

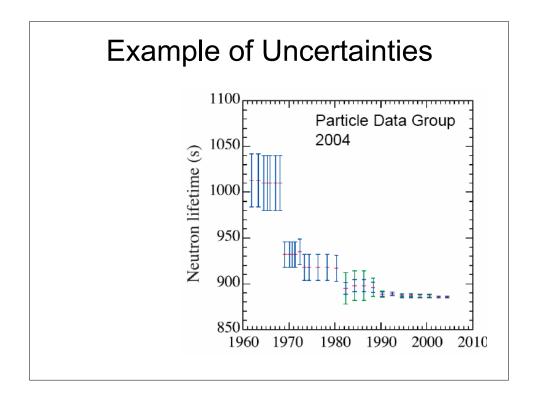
•Limited precision of a measurement device

•Uncontrolled variation of extraneous variables (eg. biology)

·Variation in amplifier output which affects measured values

•Difficulty in making a measurement

These fluctuations may or may not be strictly "random" or statistical in nature. Often we will use statistics to study these effects - which may or may not be strictly true. Much of this course focuses on designing instruments or experiments which minimize these effects.



Uncertainties

Physics 252 (or other statistics class) dealt with the random uncertainties present in all measurements, and harnessed the power of statistics to deal with them.

- Much of this is reviewed in chapter 1 of Sayer & Mansingh.

Physics 352 builds on this. How can we use physics, instrumentation and electronics to reduce and understand these uncertainties? We will still need to understand statistics, since this is the way these random fluctuations are characterized, but we will go beyond that to study why the fluctuations occur...

Next few lectures: NO/SE